

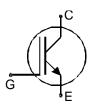
IGBT³ Chip

SIGC101T170R3

FEATURES:

- 1700V Trench + Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

- This chip is used for:
- power module
- **Applications:**
- drives



Chip Type	V _{CE}	I Cn	Die Size	Package	Ordering Code
SIGC101T170R3	1700V	75A	10.03 x 10.03 mm ²	sawn on foil	Q67050- A4188-A001

MECHANICAL PARAMETER:

Raster size	10.03 x 10.03 m			
Emitter pad size	8 x (3.82 x 1.75)			
Gate pad size	1.18 x 1.09			
Area total / active	100.6 / 75.3			
Thickness	190	μm		
Wafer size	150	mm		
Flat position	90	grd		
Max.possible chips per wafer	136 pcs			
Passivation frontside	Photoimide			
Emitter metalization	3200 nm AlSiCu			
Collector metalization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond	Al, <500µm			
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, Tj=25 °C	V _{CE}	1700	V
DC collector current, limited by T _{jmax}	I _C	1)	А
Pulsed collector current, t_p limited by T_{jmax}	I _{cpuls}	225	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T _j , T _{stg}	-55 +150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I _C = 3mA	1700			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =75A	1.6	2	2.4	V
Gate-emitter threshold voltage	V _{GE(th)}	$I_C=3mA$, $V_{GE}=V_{CE}$	5.2	5.8	6.4	
Zero gate voltage collector current	I _{CES}	V_{CE} =1700V , V_{GE} =0V			600	μΑ
Gate-emitter leakage current	I _{GES}	$V_{CE}=0V$, $V_{GE}=20V$			600	nA
Integrated gate resistor	R _{Gint}			8.5		Ω

ELECTRICAL CHARACTERISTICS (tested at component):

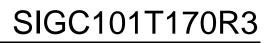
Parameter	Symbol	Conditions	Value			Unit
Farameter	Symbol		min.	typ.	max.	Onit
Input capacitance	Ciss	V _{CE} =25V,		6638		pF
Output capacitance	Coss	$V_{GE}=0V$,		277		
Reverse transfer capacitance	Crss	<i>f</i> =1MHz		220		

SWITCHING CHARACTERISTICS (tested at component), Inductive Load

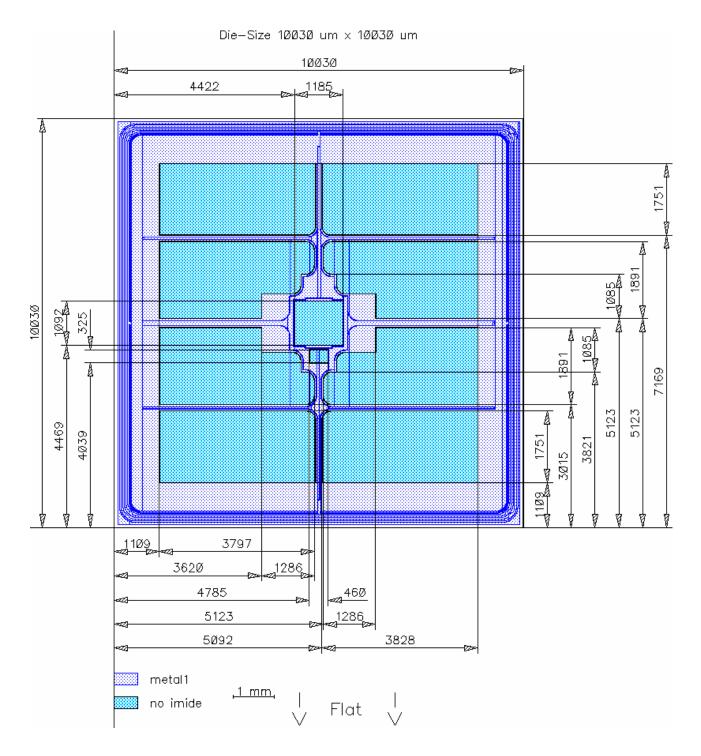
Parameter	Symbol	Conditions ¹⁾	Value			Unit
T diameter			min.	typ.	max.	
Turn-on delay time	t _{d(on)}	<i>T</i> _j =125°C		tbd		μs
Rise time	<i>t</i> r	$V_{\rm CC} = 1200 V$,		tbd		
Turn-off delay time	$t_{d(off)}$	V _{GE} =-15/15V,		tbd		
Fall time	t _f	$R_{\rm G}$ = Ω		tbd		

¹⁾ values also influenced by parasitic L- and C- in measurement and package.





CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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